

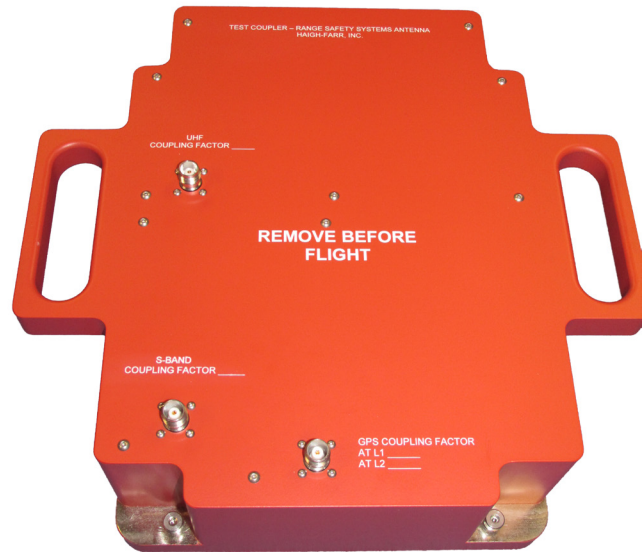


The Haigh-Farr Test Hats enable communication while containing the RF energy from an antenna.

Haigh-Farr test hats are constructed out of a solid aluminum, one-piece case with a conductive EMI gasket where the hat is in contact with the ground plane and the antenna. This provides a tight EMI seal, minimizing RF leakage, typically to -80 dB or lower.

The coupling factor is a design parameter; however, it ranges from 4 dB to 30 dB, with each hat calibrated.

Haigh-Farr hats are designed to work with single or multiband Flexislot™ and Patch antennas, as well as single or multi-channel Wraparound™ antennas.



FEATURES:

- Tight EMI seal; leakage typically -80 dB or lower
- Frequencies from UHF to X-Band
- Single or multi-band designs
- Precision fit enables repeatable electrical characteristics when mating/demating
- Secure fastening. Flange designed to naturally mate to cylindrical, conical, and curved surfaces
- SMA, TNC, and other connector options available
- Low outgassing materials utilized
- Unique mounting techniques available

APPLICATIONS:

- Contain RF energy
- Ground and lab testing
- Reduced EMI environments
- System verification
- Late stage testing with last minute removal prior to flight

DESIGN CAPABILITY:

Haigh-Farr has an over 50 year history of designing and producing exceptionally rugged, high-performance antennas. If you don't find an antenna meeting your requirements in our standard list of products, Haigh-Farr has the experience and modeling capability to customize a solution. Adaptations of existing designs can be done with very short lead times.

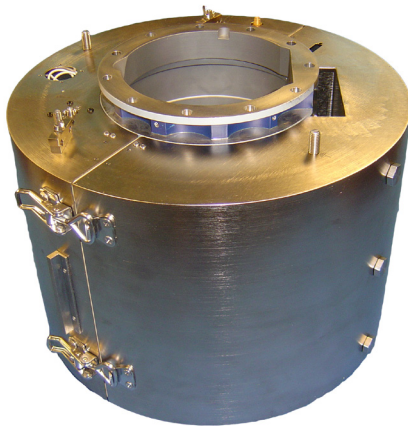
Contact Haigh-Farr for a review of your antenna requirements.



Single Channel Hat



Tri-Band Flexislot™ Hat



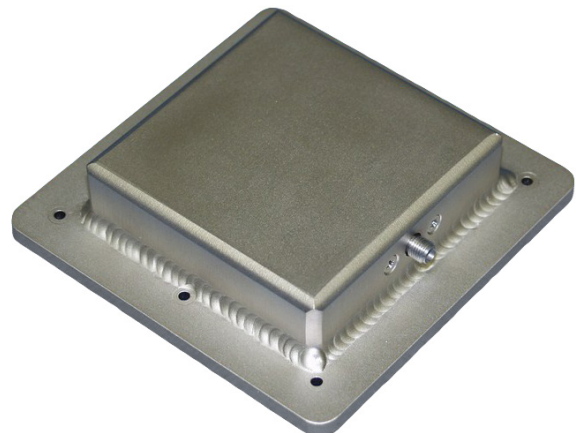
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